Silicon Vertex Detector and Time-dependent CP violation analysis at Belle

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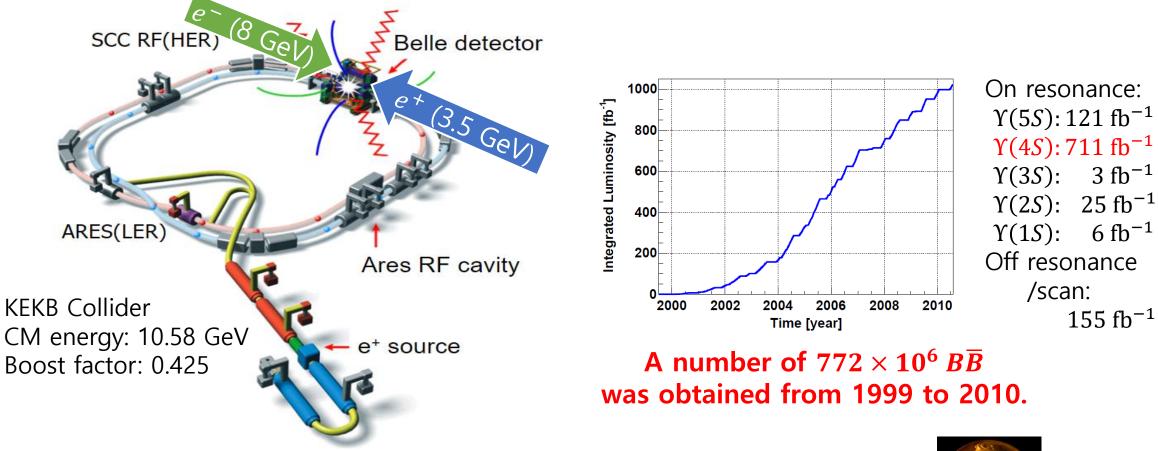




Outline

- Introduction
 - Belle experiment
 - Time dependent CP violation
- Silicon vertex detector for Belle II experiment
- Measurement of Time-dependent CP violation parameters using $B^0 \to K^0_S K^0_S K^0_S$ decay at Belle
- Summary

Introduction - Belle experiment

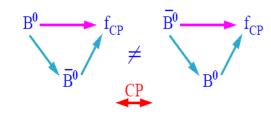


Establishing CP violation in B meson decay

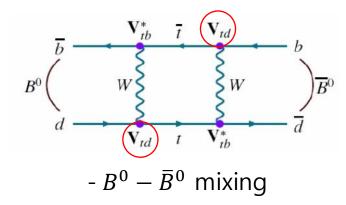


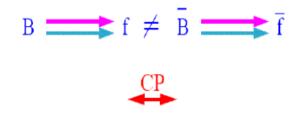
Introduction – time-dependent *CP* violation (1)

- The time-dependent *CP* violation (*TCPV*) can be caused by the interference between B^0 decay to *CP* eigenstate (f_{cp}) and $B^0 - \overline{B}^0$ mixing.



- Mixing-induced CP violation (S)



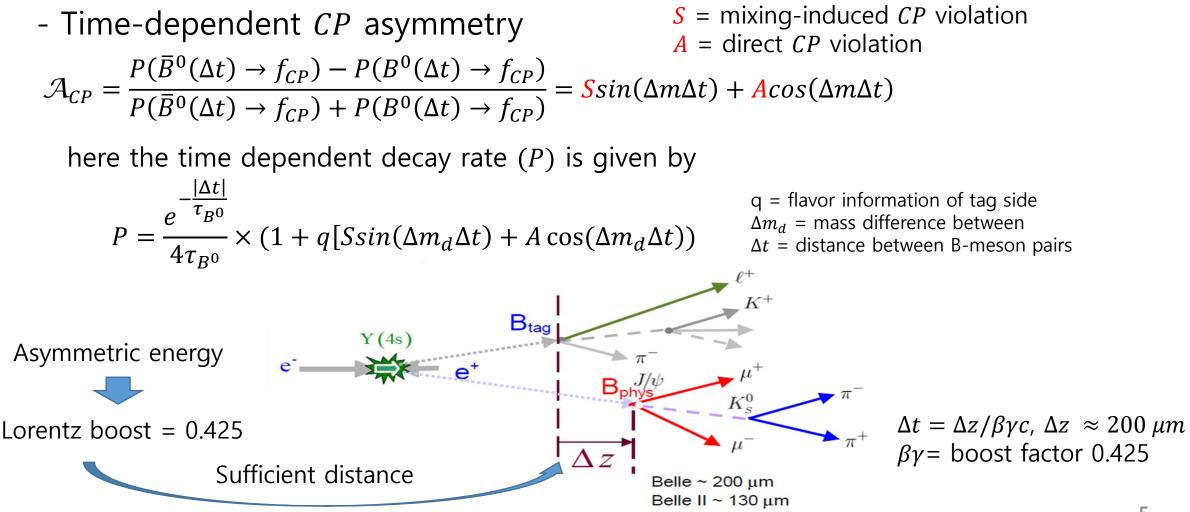


- Direct CP violation

$$V_{CKM} = \begin{pmatrix} V_{ud} & V_{us} & V_{ub} \\ V_{cd} & V_{cs} & V_{cb} \\ \hline V_{td} & V_{ts} & V_{tb} \end{pmatrix}$$
 complex phase

- CKM matrix

Introduction – time-dependent CP violation (2)



Belle II detector

EM Calorimeter: CsI(TI), waveform sampling (barrel) Pure CsI + waveform sampling (end-caps)

electron (7GeV)

Beryllium beam pipe 2cm diameter

Vertex Detector 2 layers DEPFET + 4 layers DSSD

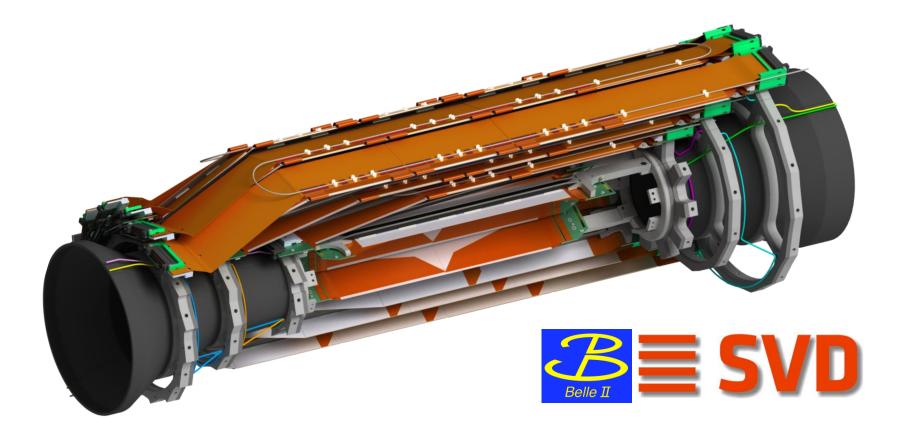
> Central Drift Chamber He(50%):C₂H₆(50%), Small cells, long lever arm, fast electronics

KL and muon detector: Resistive Plate Counter (barrel) Scintillator + WLSF + MPPC (end-caps)

Particle Identification Time-of-Propagation counter (barrel) Prox. focusing Aerogel RICH (fwd)

positron (4GeV)

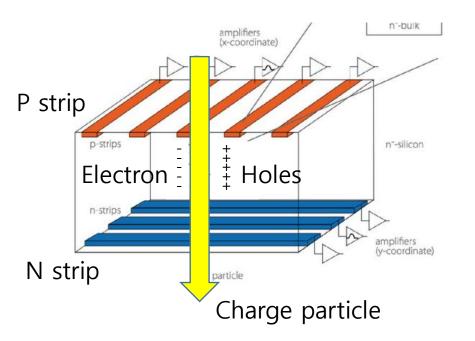




Silicon Vertex Detector @ Belle II

Silicon detector

- High resolution for
 - Position
 - Energy
 - Time

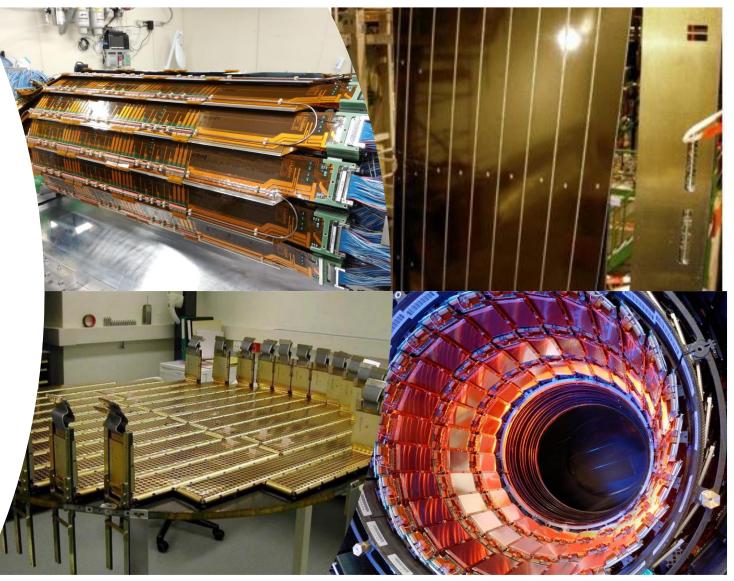






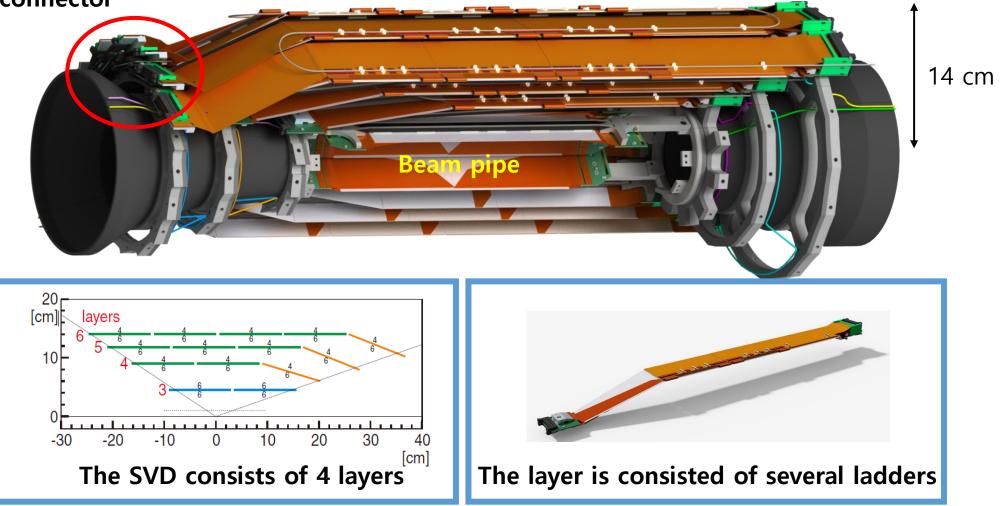
CMS

9

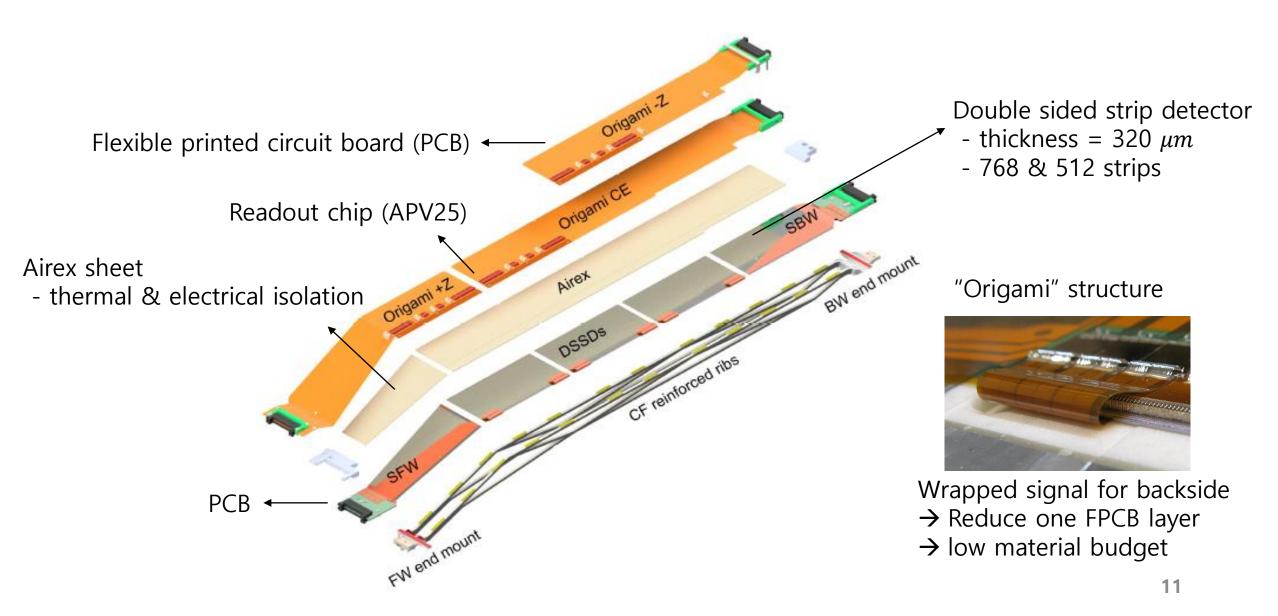


Belle II SVD overview

Readout connector

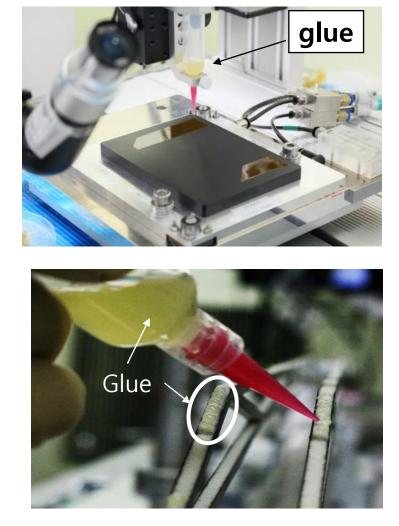


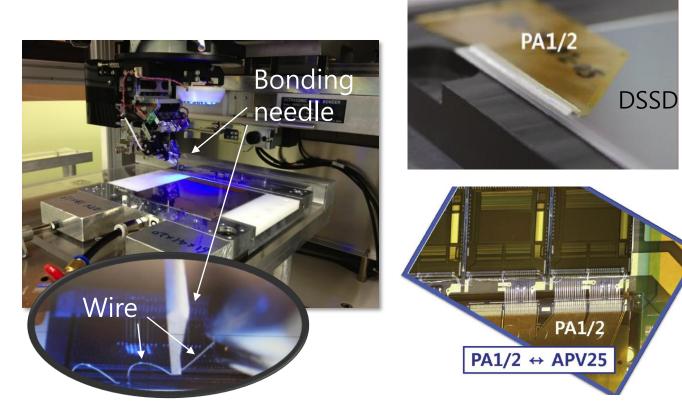
Exploded view of outmost SVD



Gluing and wire bonding

- Gluing \rightarrow for mechanical assemble
- Wire bonding \rightarrow for electrical connection



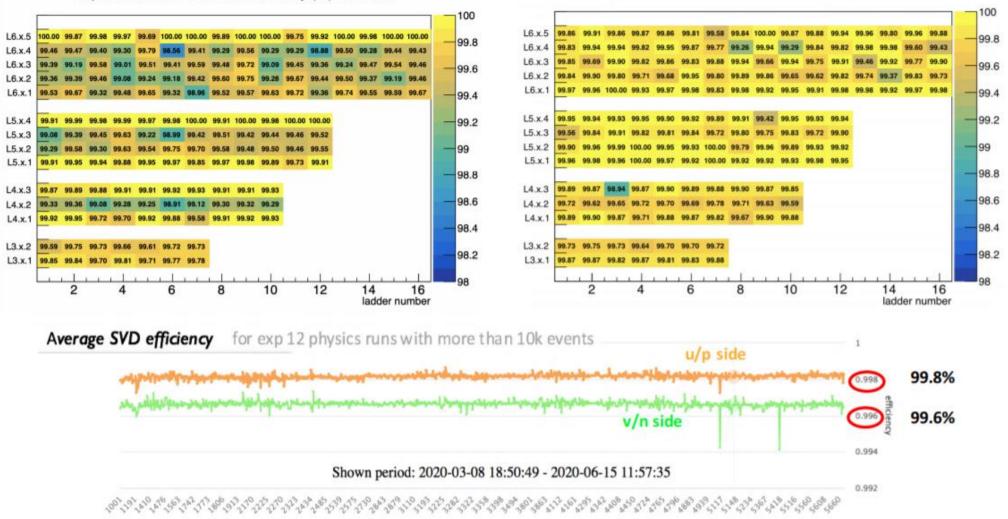


Wire diameter : 25 µm

Performance of SVD

Exp 12 Run3199 - SVD Hit Efficiency (%) U/P Side

Exp 12 Run3199 - SVD Hit Efficiency (%) V/N Side

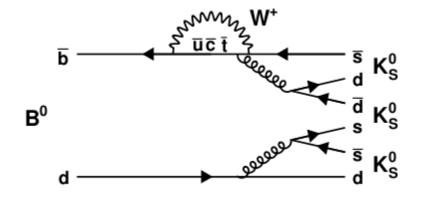


SVD assembly at IPMU

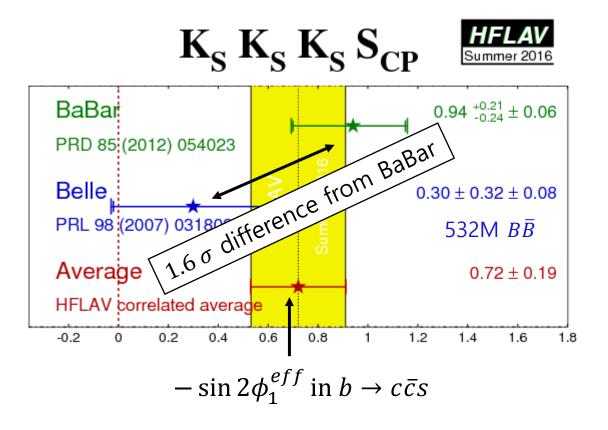


Measurement of TCPV violation parameters using $B^0 \rightarrow K_S^0 K_S^0 K_S^0$ decays at Belle arXiv (2011.00793)

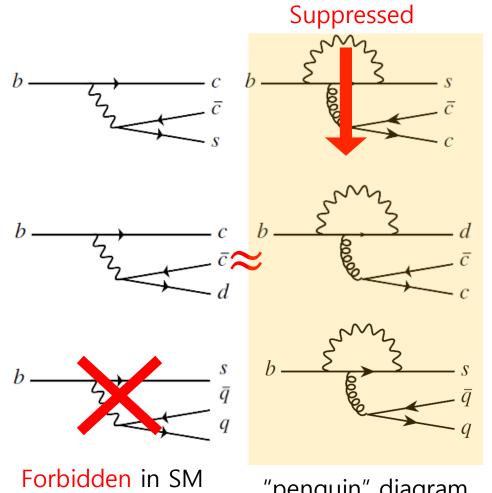
Introduction - motivation



- Pure $b \rightarrow s$ penguin transition by loop diagram
 - Sensitive to new physics
- *CP*-even eigenstate
 - $S = -\sin 2\phi_1^{eff}$
- We aim to accurately measure TCPV value in $B^0 \rightarrow K_S^0 K_S^0 K_S^0$ with final data sample (772M $B\overline{B}$).



Measurements of $\sin 2\phi_1$



 $b \rightarrow c\bar{c}s$ transition (ex: $B^0 \rightarrow J/\psi K_S^0$) sin $2\phi_1 = 0.699 \pm 0.017$ (W.A.)

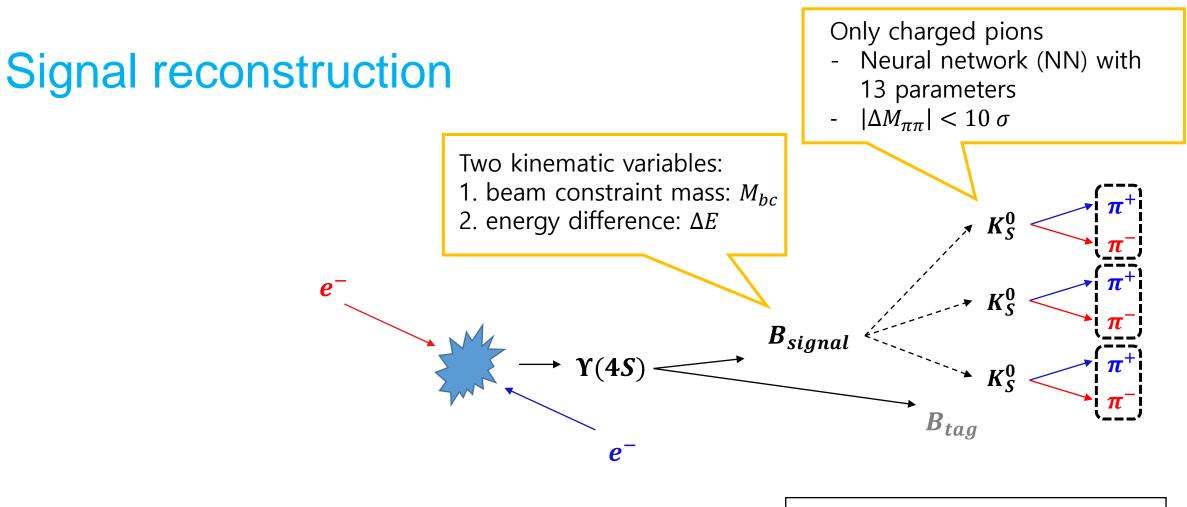
 $b \rightarrow c\bar{c}d$ transition (ex: $B^0 \rightarrow J/\psi \pi^0$, $J/\psi \rho^0$) sin $2\phi_1^{eff} = ???$

 $b \rightarrow s\bar{q}q$ penguin transition (ex: $B^0 \rightarrow \pi^0 \pi^0 K_S^0$, $K_S^0 K_S^0 K_S^0$) $\sin 2\phi_1^{eff} = ???$

dden in SM "penguin" diagram →sensitive to new physics (NP)

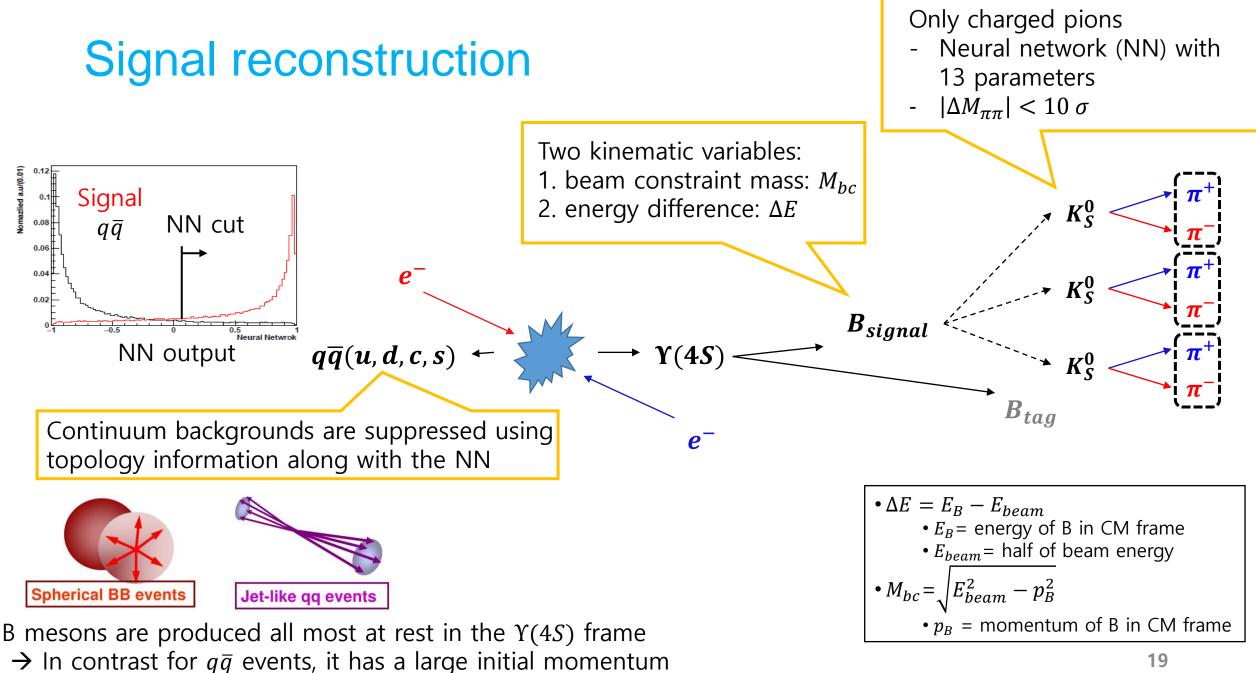
Significant deviation of $\sin 2\phi_1^{eff}$ from $\sin 2\phi_1$ indicates evidence of NP.

[Ed. A.J. Bevan, B. Golob, Th. Mannel, S. Prell, and B.D. Yabsley, Eur. Phys. J. C74 (2014) 3026]

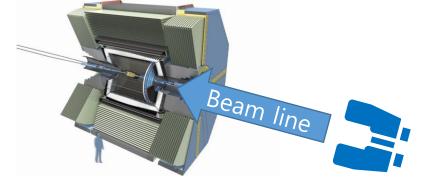


•
$$\Delta E = E_B - E_{beam}$$

• E_B = energy of B in CM frame
• E_{beam} = half of beam energy
• $M_{bc} = \sqrt{E_{beam}^2 - p_B^2}$
• p_B = momentum of B in CM frame

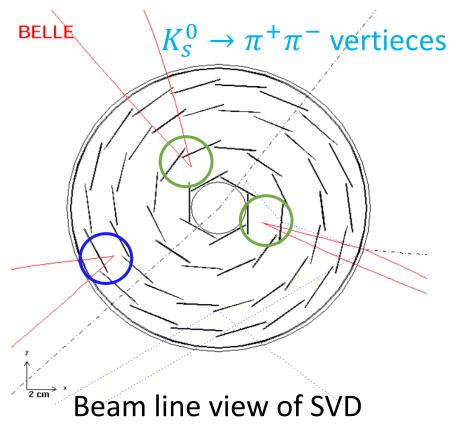


Vertex reconstruction

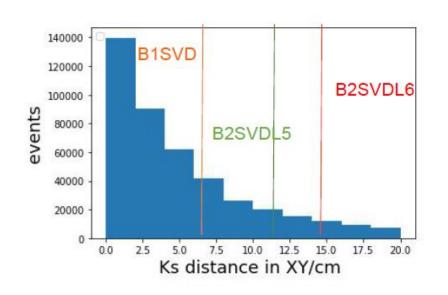


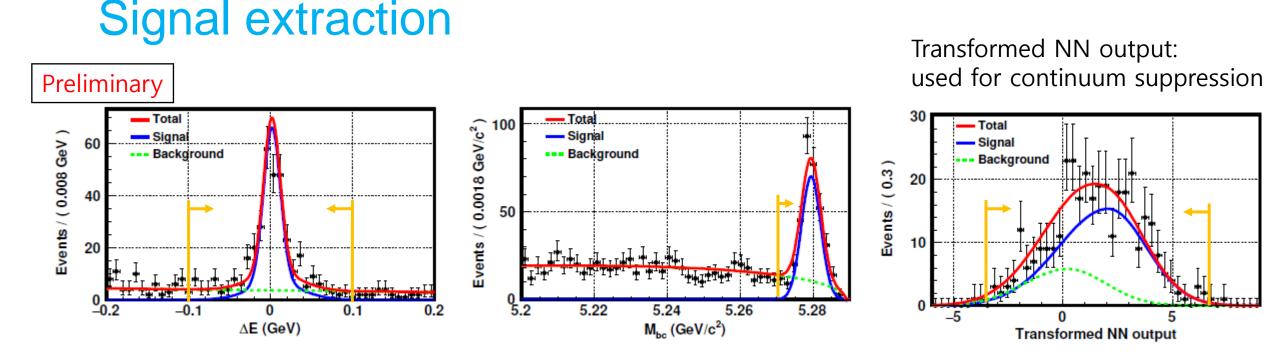
In this decay mode there is no primary charged track

ightarrow to find vertex position we make Ks trajectory using pion hit



In the Belle experiment about 40% Ks does not have any pion hit → improved at Belle II





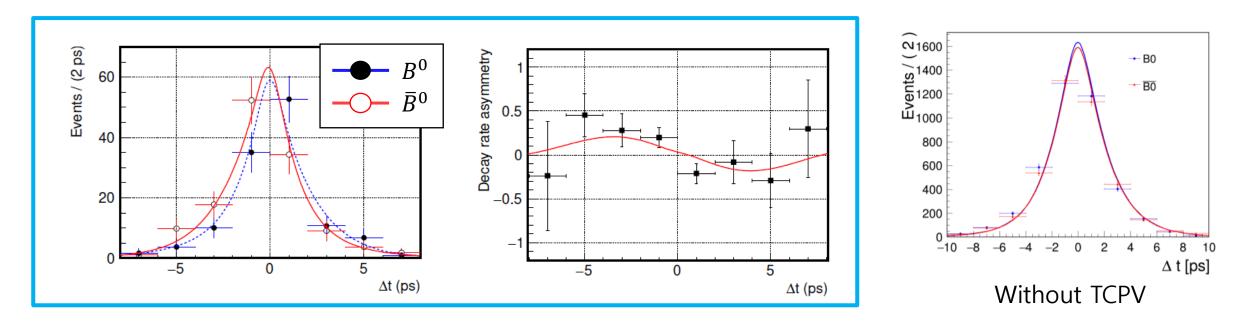
- An unbinned maximum likelihood (ML) fit with 3D PDF (ΔE , M_{bc} , Transformed NN).
- Signal $B^0 \& \overline{B}^0$ is obtained to be 258 ± 17 and the purity in the signal region is 74%.

PDF	ΔΕ	M _{bc}	Transformed NN
Signal	Double Gaussian	Gaussian	Asymmetry Gaussian
Background	1 st Polynomial	ARGUS	Asymmetry Gaussian

Measurement of TCPV parameters

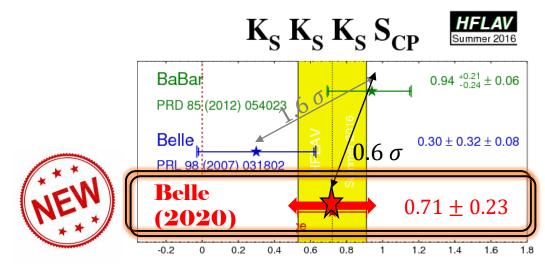
• Fitting results

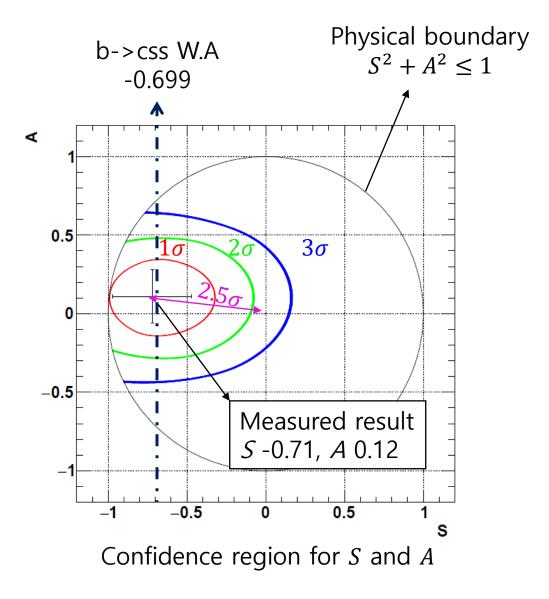
- $S = -0.71 \pm 0.23$ (stat) ± 0.05 (syst)
 - $-\sin 2\phi_1$ in $b \to c\bar{c}s = -0.699$
- $A = 0.12 \pm 0.16 \text{ (stat)} \pm 0.05 \text{ (syst)}$



Significance of CP violation

- The significance is calculated using the Feldman-Cousins approach.
 - Frequentist approach
 - ↔ Bayesian approach (PDF based on hypothesis)
- The significance of CP violation is determined to be 2.5σ away from (0,0)





Consistent with previous measurements and $b \rightarrow c\bar{c}s$

Summary

- Main purpose of Belle experiment is measurement of CP violation
 - Measurement distance between B-mesons is important
 - Silicon vertex detector provides good vertex resolution for TCPV analysis
- Belle II SVD
 - SVD was installed in the Belle II detector in Nov. 2018
 - During physics run, SVD has been operated smoothly
- The measurements of time-dependent *CP* violation in $B^0 \rightarrow K_S^0 K_S^0 K_S^0$ decays using the final data sample (772 × 10⁶ $B\overline{B}$):
 - $S = -0.72 \pm 0.23$ (stat) ± 0.05 (syst)
 - $A = 0.11 \pm 0.16 \text{ (stat)} \pm 0.05 \text{ (syst)}$
 - The results are consistent with SM expectation and previous Belle result

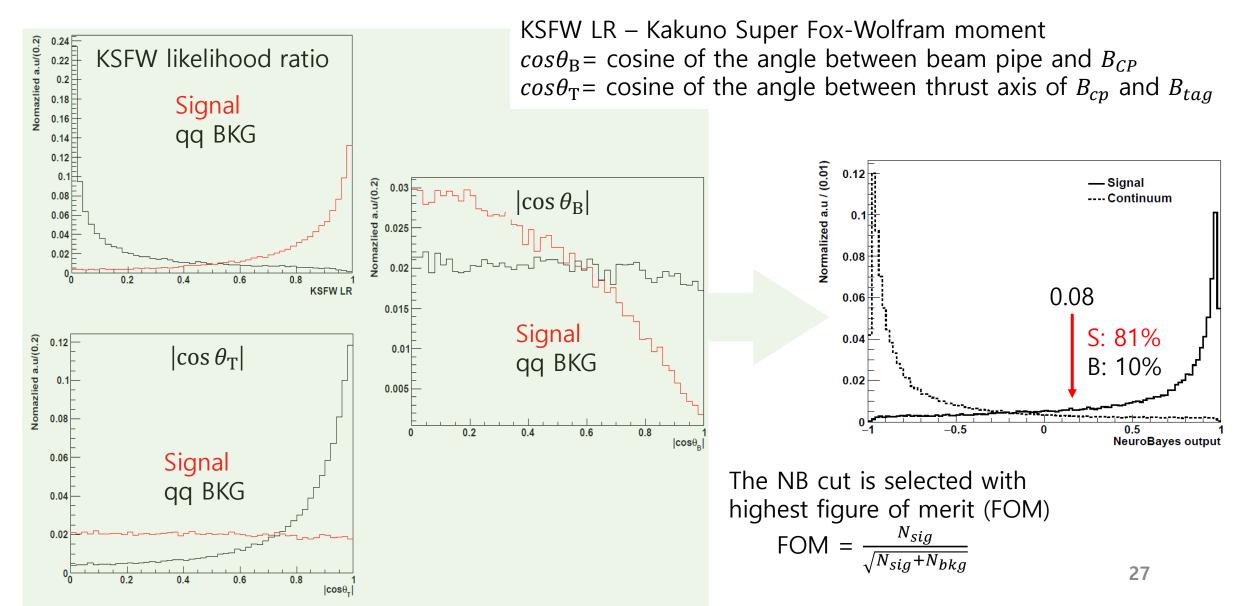
Backup

Signal reconstruction – selection criteria and best candidate selection

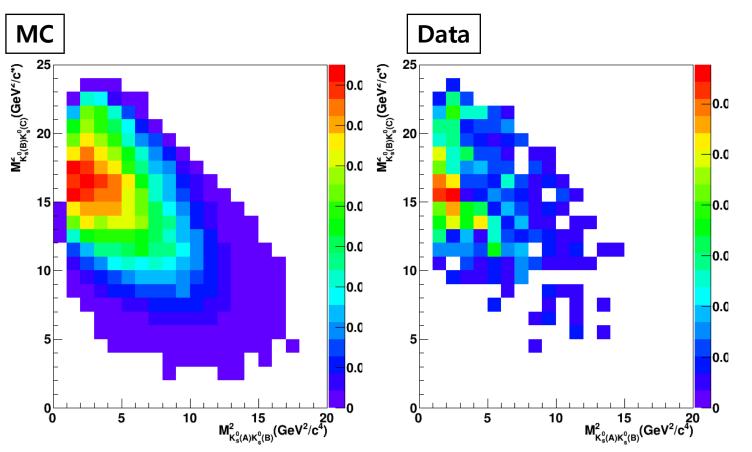
- We use K_S^0 only from charged decay to avoid background.

	$B^0 ightarrow K^0_S K^0_S K^0_S$
$K_S^0(\pi^+\pi^-)$ selection in mdst_vee2	$ \Delta M_{\pi\pi} < 10 \sigma$, nisKsfinder cut (nb_vlike>0.2)
$\Delta E \; [GeV]$	$-0.2 < \Delta E < 0.2$
$M_{bc} [GeV/c^2]$	5.2 < M_{bc}
Best candidate selection	smallest of $\chi^2 = \sum_{i=1}^3 \left(\frac{M_{\pi\pi}^i - M_{K_S^0}}{\sigma_{\pi\pi}} \right)^2$
Continuum BKG suppression	KSFW LR, cosθ _B , cosθ _T NeuroBayes output>0.08

Continuum background

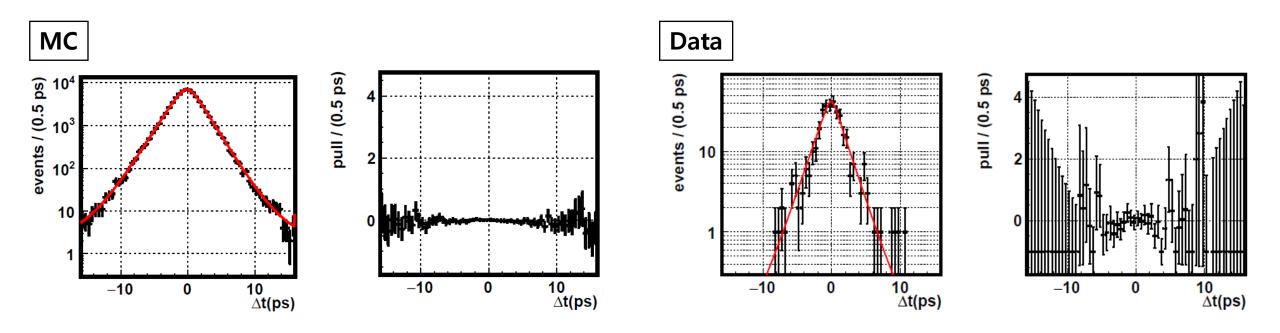


Dalitz plot



• Compare the dalitz plot for MC and data, our evtgen model for MC generation, PHSP_CP, well describes data.

CP fitting – lifetime measurement



- Using 1M signal MC with input τ_B is 1.5367
 - Fitting result: 1.5461 ± 0.0072 ps
 - Difference (fitting result input) : 0.0106 ps
- Data result
 - Fitting result: 1.4271 ± 0.1129 ps
 - PDG value $(1.520 \pm 0.004 \text{ ps})$

The result of lifetime fitting is consistent with PDG value

Systematic error

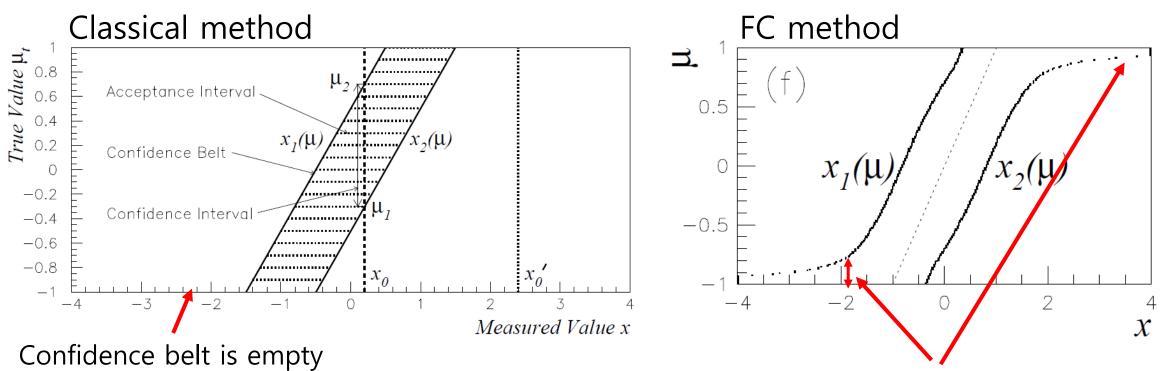
Source	S	A
Vertex reconstruction	0.031	0.038
Flavor tagging	0.002	0.004
Resolution function	0.016	0.014
Physics parameters	0.004	0.001
Fit bias	0.012	0.009
Signal fraction	0.024	0.021
Background Δt shape	0.016	0.001
SVD misalignment	0.004	0.005
Δz bias	0.002	0.004
Tag-side interference	0.001	0.008
Total	0.05	0.05

Main source of systematic error comes from non-primary charged track.

But statistical error is much larger than systematic.

- statistics: S(0.23), A(0.16)

Classical and FC frequentist



when measured value x is far from physical region

Confidence belt is never empty! By ordering principle